

## Publications List

1. **Study of metal release from stain-less steels in simulated food con-tact by means of total reflection X-ray fluorescence**, *R Dalipi, L Borgese, A Casaroli, M Boniardi, U Fittschen, K Tsuji, LE Depero*, Journal of Food Engineering (2016)
2. **Total reflection X-Ray fluorescence spectroscopy to study Pb and Zn accumulation in zebrafish embryos**, *Bilo, F., Moscoso, S., Borgese, L., Delbarba, M.V., Zacco, A., Bosio, A., Federici, S., Guarienti, M., Pre-sta, M., Bontempi, E., Depero, L.E.*, X-Ray Spectrometry (2015)
3. **Total reflection X-ray fluorescence as a tool for food screening**, *Borgese, L., Bilo, F., Dalipi, R., Bon-tempi, E., Depero, L.E.*, Spectrochimica Acta - Part B Atomic Spectroscopy (2015)
4. **Determination of trace elements in Italian wines by means of total reflection X-ray fluorescence spectroscopy**, *Dalipi, R., Borgese, L., Zacco, A., Tsuji, K., Sangiorgi, E., Piro, R., Bontempi, E., Depero, L.E.*, International Journal of Environmental Analytical Chemistry (2015)
5. **Total Reflection X-Ray Fluores-cence Spectroscopy to Evaluate Heavy Metals Accumulation in Legumes**, *Fabjola Bilo, Laura Borgese, Anna-lisa Zacco, Pranvera Lazo, Claudia Zoani, Giovanna Zappa, Elza Bon-tempi and Laura E Depero*, Journal of Analytical and Bioanalytical techniques (2015)
6. **Measuring Compositions in Organic Depth Profiling: Results from a VAMAS Interlaboratory Study**, *AG Shard, R Havelund, SJ Spencer, IS Gilmore, MR Alexander, TB Angerer, S Aoyagi, J-P Barnes, A Benayad, A Bernasik, G Ceccone, JDP Counsell, C Deeks, JS Fletcher, DJ Graham, C Heuser, T G Lee, C Marie, MM Marzec, G Mishra, D Rading, O Renault, DJ Scurr, HK Shon, V Spampinato, H Tian, F Wang, N Winograd, K Wu, A Wucher, Y Zhou, Z Zhu, V Cristaudo, C Poleunis*, The Journal of Physical Chemistry B 119, 33, 10784- 10797 (2015).
7. **Sputtering Yields for Mixtures of Organic Materials Using Argon Gas Cluster Ions**, *MP Seah, R Havelund, AG Shard, IS Gilmore*, The Journal of Physical Chemistry B 119, 42, 13433- 13439 (2015).
8. **Interlaboratory study comparing analyses of simulated angle-resolved X-ray photoelectron spectroscopy data**, *G. Tasneem, W. S. M. Werner, W. Smekal and C. J. Powell*, Surf. Interface Anal., 46, 321–332 (2014).
9. **Efficiency of automated peak identification with daily used commercial software for X-ray photoelectron spectra - report from VAMAS/TWA 2/A 9 project**, *Mineharu Suzuki, Sei Fukushima, Shigeo Tanuma*, Surface and Interface Analysis (DOI: 10.1002/sia.5245) (2013)
10. **Linearity of the instrumental intensity scale in ToF-SIMS – A VAMAS Interlaboraotry Study**, *J. L. S. Lee, I. S. Gilmore and M. P. Seah*. Surf. Interface Anal. 44, 1–14 (2012)

11. **Argon Cluster Ion Beams for Organic Depth Profiling: Results from a VAMAS Interlaboratory Study**, A. G. Shard, R. Havelund, M. P. Seah, S. J. Spencer, I. S. Gilmore, N. Winograd, D. Mao, T. Miyayama, E. Niehuis, D. Rading, R. Moellers., *Analytical Chemistry*, 84, 7865-7873 (2012)
12. **Dual beam depth profiling of organic materials: Variations of analysis and sputter beam conditions**, D. Rading, R. Moellers, F. Kollmer, W. Paul, E. Niehuis, *Surf. Interface Anal.*, 43, 198-200, (2011).
13. **Sample cooling or rotation improves C60 organic depth profiles of multi-layered reference samples: Results from a VAMAS interlaboratory study**, P. Sjövall, D. Rading, S. Ray, L. Yang and A. G. Shard: *J. Phys. Chem. B*, 114, 769-774, (2011).
14. **VAMAS Interlaboratory Study on Organic Depth Profiling 1: Preliminary Report**, A. G. Shard, R. Foster, I. S. Gilmore, J. L. S. Lee, S. Ray, L. Yang: *Surf. Interface Anal.*, 43, 510-513, (2011).
15. **Organic Depth Profiling of a Nanostructured Delta Layer Reference Material Using Large Argon Cluster Ions**, J. L. S. Lee, S. Ninomiya, J. Matsuo, I. S. Gilmore, M. P. Seah, and A. G. Shard: *Anal. Chem.*, 82, 98–105 (2010)
16. **Molecular Depth Profiling with Cluster Secondary Ion Mass Spectrometry and Wedges**, Dan Mao, Andreas Wucher and Nicholas Winograd: *Anal. Chem.*, 82, 57–60. (2010)
17. **Incident Angle Dependence in Polymer TOF-SIMS Depth Profiling with C60 Ion Beams**, Shin-ichi Iida, Takuya Miyayama, Noriaki Sanada, Mineharu Suzuki, Gregory L. Fisher and Scott R. Bryan: *e-J.*, *Surf. Sci. Nanotech.* Vol. 7, 878-881 (2009)
18. **Evaluation of Uncertainties in X-ray Photoelectron Spectroscopy Intensities Associated with Different Methods and Procedures for Background Subtraction. I. Spectra for Monochromatic Al X-rays**, Powell, C. J. and Conny, J. M., *Surf. Interface Anal.* 41, 269 (2009).
19. **X-ray reflectivity and total reflection x-ray fluorescence study of surface oxide evolution in a GaAs/AlAs multilayer system**, Paolo Colombi, Elza Bontempi, Laura E. Depero, Yasushi Azuma, and Toshiyuki Fujimoto, *Journal of Applied Physics*, 105, 014307 (2009).
20. **Reproducibility in X-ray Reflectometry: Results from the First World-Wide Round-Robin Experiment**, P. Colombi, D. K. Agnihotri, V. E. Asadchikov, E. Bontempi, D. K. Bowen, C. H. Chang, L. E. Depero, M. Farnworth, T. Fujimoto, A. Gibaud, M. Jergel, M. Krumrey, T. A. Lafford, A. Lamperti, T. Ma, R. J. Matyi, M. Meduna, S. Milita, Kenji Sakurai, L. Shabelnikov, Ulyanenko, A. Van der Lee, and C. Wiemer, *J. Appl. Cryst.* 41, 143 (2008).
21. **Surface Roughness and Island Formation effects in ARXPS quantification**, A.I. Martín-Concepción, F. Yubero, J.P. Espinos, J. Garcia, and S. Tougaard, *Surf. Interface Anal.*, 36, 788 (2004).

22. **Determination of amount of substance for nanometre thin deposits; Consistency between XPS, RBS, and XRF quantification**, *A.I. Martin-Concepción, F. Yubero, J.P. Espinós, A.R. González-Elipe, S. Tougaard*, Surf. Interface Anal. **35**, 984 (2003).
23. **QUASES-ARXPS software package**, Vers. 2.1 [for details see: [www.quases.com](http://www.quases.com) where the manual which gives the details of the analysis can be freely downloaded]. (2002)
24. **Comparison of the Tougaard, ARXPS, RBS and Ellipsometry methods to determine the thickness of thin SiO<sub>2</sub> layers**, *B. S. Semak, C. van der Marel and S. Tougaard*, Surf. Interface Anal. **33**, 238 (2002).
25. **Practical Correction Procedures for Elastic Electron Scattering Effects in ARXPS**, *T.S. Lassen, S. Tougaard, A. Jablonski*, Surf. Sci. **481**, 150 (2001).
26. **VAMAS round robin study to evaluate a correction method for saturation effect in DSIMS**, *Takano, H. Nonaka, Y. Homma, M. Tomita, A. Murase, S. Hayashi, M. Barozzi, K. J.*

*Kim, D. Sykes D. Simons, J. Bennett, C. W. Magee, Surf. Interface Anal. (2014), DOI 10.1002/sia5537, which was described as an accepted paper in the last year's annual report.*

30. **Final report on VAMAS round robin study to evaluate a correction method for saturation effect in DSIMS**, Surface and Interface Analysis (Accepted on March 5, 2015).
31. **Nano-palpatation AFM and its quantitative mechanical property mapping**, Microscopy, 63, 193-207 (2014).
32. **VAMAS Interlaboratory Study for Desorption Electrospray Ionization Mass Spectrometry (DESI MS) Intensity Repeatability and Constancy**, *Elzbieta Gurdak, Felicia M. Green, Paulina D. Rakowska, Martin P. Seah, Tara L. Salter, Ian S. Gilmore, Anal. Chem., dx.doi.org/10.1021/ac502075t, Anal. Chem., 86, 9603–9611, 2014*